#### **Features**

- Low-voltage and Standard-voltage Operation
  - 2.7 (V<sub>CC</sub> = 2.7V to 5.5V)
  - 1.8 (V<sub>CC</sub> = 1.8V to 5.5V)
- User-selectable Internal Organization
  - 1K: 128 x 8 or 64 x 16
  - 2K: 256 x 8 or 128 x 16
  - 4K: 512 x 8 or 256 x 16
- 3-wire Serial Interface
- 2 MHz Clock Rate (5V)
- Self-timed Write Cycle (10 ms max)
- High Reliability
  - Endurance: 1 Million Write Cycles
  - Data Retention: 100 Years
- Automotive Grade, Extended Temperature and Lead-Free/Halogen-Free **Devices Available**
- 8-lead PDIP, 8-lead JEDEC SOIC, 8-lead EIAJ SOIC, 8-lead MAP, 8-lead TSSOP and 8-ball dBGA2<sup>™</sup> Packages

### Description

The AT93C46/56/66 provides 1024/2048/4096 bits of serial electrically erasable programmable read only memory (EEPROM), organized as 64/128/256 words of 16 bits each when the ORG pin is connected to VCC, and 128/256/512 words of 8 bits each when it is tied to ground. The device is optimized for use in many industrial and commercial applications where low-power and low-voltage operations are essential. The AT93C46/56/66 is available in space-saving 8-lead PDIP, 8-lead JEDEC SOIC, 8-lead EIAJ SOIC, 8-lead MAP, 8-lead TSSOP, and 8-ball dBGA2<sup>™</sup> packages.

### **Pin Configurations**

Pin Name	Function			
CS	Chip Select			
SK	Serial Data Clock			
DI	Serial Data Input			
DO	Serial Data Output			
GND	Ground			
VCC	Power Supply			
ORG	Internal Organization			
DC	Don't Connect			

8-lead	SOIC	
1	8	
2	7	
3	6	🔤 ORG
4	5	🔤 GND
	1 2	2 7 3 6

8-lead PDIP





	VCC 🗖
5 🗆 GND	CS 🗆
	SK 🖂
P	
_	
	Г

VCC	8		CS
DC	7	2	SK
ORG	6	3	DI
GND		4	DO

GND 5	(4) D0
(Botto	m view)
8-lead	d SOIC
Rotat	ted (R)
(1K JEC	EC Only)
DC 🖂 1	8 🗔 ORG
CC 🗖 2	7 🗖 GND
CS 🖂 3	6 🗖 DO
SK 🖂 4	5 🗖 DI
0 1	TOOOD
8-lead	TSSOP

8-ball dBGA2

VCC 8

CND

DC

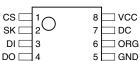
ORG 6

 $\bigcirc$ 

① CS

2 SK

③ D1





# **3-wire Serial EEPROMs**

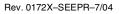
1K (128 x 8 or 64 x 16)

2K (256 x 8 or 128 x 16)

4K (512 x 8 or 256 x 16)

# AT93C46 AT93C56<sup>(1)</sup> AT93C66<sup>(2)</sup>

- Note: 1. This device is not recommended for new designs. Please refer to AT93C56A.
  - 2. This device is not recommended for new designs. Please refer to AT93C66A.







The AT93C46/56/66 is enabled through the Chip Select pin (CS) and accessed via a 3-wire serial interface consisting of Data Input (DI), Data Output (DO), and Shift Clock (SK). Upon receiving a READ instruction at DI, the address is decoded and the data is clocked out serially on the DO pin. The WRITE cycle is completely self-timed and no separate ERASE cycle is required before WRITE. The WRITE cycle is only enabled when the part is in the ERASE/WRITE ENABLE state. When CS is brought "high" following the initiation of a WRITE cycle, the DO pin outputs the READY/BUSY status of the part.

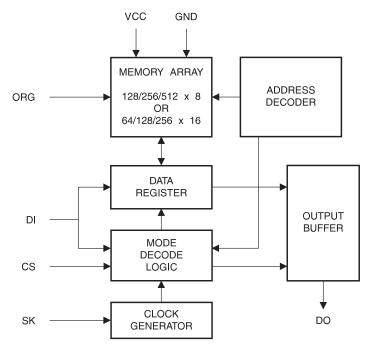
The AT93C46/56/66 is available in 2.7V to 5.5V and 1.8V to 5.5V versions.

#### Absolute Maximum Ratings\*

Operating Temperature55°C to +125°C
Storage Temperature65°C to +150°C
Voltage on Any Pin with Respect to Ground1.0V to +7.0V
Maximum Operating Voltage 6.25V
DC Output Current 5.0 mA

\*NOTICE: Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress rating only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability

#### **Block Diagram**



- Note: 1. When the ORG pin is connected to VCC, the x 16 organization is selected. When it is connected to ground, the x 8 organization is selected. If the ORG pin is left unconnected and the application does not load the input beyond the capability of the internal 1 Meg ohm pullup, then the x 16 organization is selected. The feature is not available on the 1.8V devices.
  - 2. For the AT93C46, if x 16 organization is the mode of choice and Pin 6 (ORG) is left unconnected, Atmel recommends using the AT93C46A device. For more details, see the AT93C46A datasheet.

# Pin Capacitance<sup>(1)</sup>

Applicable over recommended operating range from  $T_A = 25^{\circ}C$ , f = 1.0 MHz,  $V_{CC} = +5.0V$  (unless otherwise noted).

Symbol	Test Conditions	Max	Units	Conditions
C <sub>OUT</sub>	Output Capacitance (DO)	5	pF	$V_{OUT} = 0V$
C <sub>IN</sub>	Input Capacitance (CS, SK, DI)	5	pF	$V_{IN} = 0V$

Note: 1. This parameter is characterized and is not 100% tested.

### **DC Characteristics**

Applicable over recommended operating range from:  $T_{AI} = -40^{\circ}C$  to  $+85^{\circ}C$ ,  $V_{CC} = +1.8V$  to +5.5V,  $T_{AE} = -40^{\circ}C$  to  $+125^{\circ}C$ ,  $V_{CC} = +1.8V$  to +5.5V (unless otherwise noted).

Symbol	Parameter	Test Condition		Min	Тур	Max	Unit
V <sub>CC1</sub>	Supply Voltage			1.8		5.5	V
V <sub>CC2</sub>	Supply Voltage			2.7		5.5	۷
V <sub>CC3</sub>	Supply Voltage			4.5		5.5	V
	Querra la Querra et	<u> хи с ох</u> и	READ at 1.0 MHz		0.5	2.0	mA
I <sub>CC</sub>	Supply Current	$V_{CC} = 5.0V$	WRITE at 1.0 MHz		0.5	2.0	mA
I <sub>SB1</sub>	Standby Current	$V_{\rm CC} = 1.8V$	CS = 0V		0	0.1	μA
I <sub>SB2</sub>	Standby Current	$V_{\rm CC} = 2.7 V$	CS = 0V		6.0	10.0	μA
I <sub>SB3</sub>	Standby Current	V <sub>CC</sub> = 5.0V CS = 0V			17	30	μA
IL	Input Leakage	$V_{IN} = 0V$ to $V_{CC}$			0.1	1.0	μA
I <sub>OL</sub>	Output Leakage	$V_{IN} = 0V$ to $V_{CC}$	$V_{IN} = 0V$ to $V_{CC}$		0.1	1.0	μA
V <sub>IL1</sub> <sup>(1)</sup> V <sub>IH1</sub> <sup>(1)</sup>	Input Low Voltage Input High Voltage	$2.7V \le V_{CC} \le 5.5V$		-0.6 2.0		0.8 V <sub>CC</sub> + 1	V
V <sub>IL2</sub> <sup>(1)</sup> V <sub>IH2</sub> <sup>(1)</sup>	Input Low Voltage Input High Voltage	$1.8V \le V_{CC} \le 2.7V$	$1.8V \le V_{CC} \le 2.7V$			V <sub>CC</sub> x 0.3 V <sub>CC</sub> + 1	V
V <sub>OL1</sub>	Output Low Voltage		I <sub>OL</sub> = 2.1 mA			0.4	V
V <sub>OH1</sub>	Output High Voltage	$2.7V \le V_{CC} \le 5.5V$ $I_{OH} = -0.4 \text{ mA}$		2.4			V
V <sub>OL2</sub>	Output Low Voltage		I <sub>OL</sub> = 0.15 mA			0.2	V
V <sub>OH2</sub>	Output High Voltage	$1.8V \le V_{CC} \le 2.7V$	I <sub>OH</sub> = -100 μA	V <sub>CC</sub> – 0.2			V

Note: 1.  $V_{IL}$  min and  $V_{IH}$  max are reference only and are not tested.





### **AC Characteristics**

Applicable over recommended operating range from  $T_{AI} = -40^{\circ}C$  to  $+ 85^{\circ}C$ ,  $T_{AE} = -40^{\circ}C$  to  $+125^{\circ}C$ ,  $V_{CC} = As$  Specified, CL = 1 TTL Gate and 100 pF (unless otherwise noted).

Symbol	Parameter Test Condition		Min	Тур	Max	Units	
f <sub>sк</sub>	SK Clock Frequency	$\begin{array}{l} 4.5V \leq V_{CC} \; \leq \; 5.5V \\ 2.7V \leq V_{CC} \; \leq \; 5.5V \\ 1.8V \leq V_{CC} \; \leq \; 5.5V \\ \end{array}$		0 0 0		2 1 0.25	MHz
t <sub>SKH</sub>	SK High Time	$\begin{array}{l} 4.5V \leq V_{CC} \leq 5.5V \\ 2.7V \leq V_{CC} \leq 5.5V \\ 1.8V \leq V_{CC} \leq 5.5V \end{array}$		250 250 1000			ns
t <sub>SKL</sub>	SK Low Time	$\begin{array}{l} 4.5V \leq V_{CC} \ \leq 5.5V \\ 2.7V \leq V_{CC} \ \leq 5.5V \\ 1.8V \leq V_{CC} \ \leq 5.5V \end{array}$		250 250 1000			ns
t <sub>cs</sub>	Minimum CS Low Time	$\begin{array}{l} 4.5V \leq V_{CC} \ \leq 5.5V \\ 2.7V \leq V_{CC} \ \leq 5.5V \\ 1.8V \leq V_{CC} \ \leq 5.5V \end{array}$		250 250 1000			ns
t <sub>CSS</sub>	CS Setup Time	Relative to SK	$\begin{array}{l} 4.5V \leq V_{CC} \leq 5.5V \\ 2.7V \leq V_{CC} \leq 5.5V \\ 1.8V \leq V_{CC} \leq 5.5V \end{array}$	50 50 200			ns
t <sub>DIS</sub>	DI Setup Time	Relative to SK	$\begin{array}{l} 4.5V \leq V_{CC} \leq 5.5V \\ 2.7V \leq V_{CC} \leq 5.5V \\ 1.8V \leq V_{CC} \leq 5.5V \end{array}$	100 100 400			ns
t <sub>CSH</sub>	CS Hold Time	Relative to SK		0			ns
t <sub>DIH</sub>	DI Hold Time	Relative to SK	$\begin{array}{l} 4.5V \leq V_{CC} \leq 5.5V \\ 2.7V \leq V_{CC} \leq 5.5V \\ 1.8V \leq V_{CC} \leq 5.5V \end{array}$	100 100 400			ns
t <sub>PD1</sub>	Output Delay to "1"	AC Test	$\begin{array}{l} 4.5V \leq V_{CC} \leq 5.5V \\ 2.7V \leq V_{CC} \leq 5.5V \\ 1.8V \leq V_{CC} \leq 5.5V \end{array}$			250 250 1000	ns
t <sub>PD0</sub>	Output Delay to "0"	AC Test	$\begin{array}{l} 4.5V \leq V_{CC} \leq 5.5V \\ 2.7V \leq V_{CC} \leq 5.5V \\ 1.8V \leq V_{CC} \leq 5.5V \end{array}$			250 250 1000	ns
t <sub>sv</sub>	CS to Status Valid	AC Test	$\begin{array}{l} 4.5V \leq V_{CC} \leq 5.5V \\ 2.7V \leq V_{CC} \leq 5.5V \\ 1.8V \leq V_{CC} \leq 5.5V \end{array}$			250 250 1000	ns
t <sub>DF</sub>	CS to DO in High Impedance	$\begin{array}{c} \text{AC Test} \\ \text{CS} = \text{V}_{\text{IL}} \end{array} \qquad \begin{array}{c} 4.5 \text{V} \leq \text{V}_{\text{CC}} \leq 5.5 \text{V} \\ 2.7 \text{V} \leq \text{V}_{\text{CC}} \leq 5.5 \text{V} \\ 1.8 \text{V} \leq \text{V}_{\text{CC}} \leq 5.5 \text{V} \\ \end{array}$				100 100 400	ns
+	Write Cuele Time					10	ms
t <sub>WP</sub>	Write Cycle Time		$4.5V \leq V_{CC} \leq 5.5V$	0.1	3		ms
Endurance <sup>(1)</sup>	5.0V, 25°C, Page Mo	de		1M			Write Cycles

Note: 1. This parameter is characterized and is not 100% tested.

#### Instruction Set for the AT93C46

		Ор	Add	Address		ata	
Instruction	SB	Code	x 8	x 16	x 8	x 16	Comments
READ	1	10	$A_6 - A_0$	$A_{5} - A_{0}$			Reads data stored in memory, at specified address.
EWEN	1	00	11XXXXX	11XXXX			Write enable must precede all programming modes.
ERASE	1	11	$A_6 - A_0$	$A_{5} - A_{0}$			Erase memory location $A_n - A_0$ .
WRITE	1	01	$A_6 - A_0$	$A_{5} - A_{0}$	$D_7 - D_0$	D <sub>15</sub> – D <sub>0</sub>	Writes memory location $A_n - A_0$ .
ERAL	1	00	10XXXXX	10XXXX			Erases all memory locations. Valid only at $V_{CC} = 4.5V$ to 5.5V.
WRAL	1	00	01XXXXX	01XXXX	D <sub>7</sub> – D <sub>0</sub>	D <sub>15</sub> - D <sub>0</sub>	Writes all memory locations. Valid only at $V_{CC} = 4.5V$ to 5.5V.
EWDS	1	00	00XXXXX	00XXXX			Disables all programming instructions.

Note: The X's in the address field represent don't care values and must be clocked.

### Instruction Set for the AT93C56<sup>(1)</sup> and AT93C66<sup>(2)</sup>

		Ор	Address <sup>(3)</sup>		Data		
Instruction	SB	Code	x 8	x 16	x 8	x 16	Comments
READ	1	10	$A_8 - A_0$	A <sub>7</sub> – A <sub>0</sub>			Reads data stored in memory, at specified address.
EWEN	1	00	11XXXXXXX	11XXXXXX			Write enable must precede all programming modes.
ERASE	1	11	A <sub>8</sub> -A <sub>0</sub>	$A_7 - A_0$			Erase memory location $A_n - A_0$ .
WRITE	1	01	A <sub>8</sub> -A <sub>0</sub>	$A_7 - A_0$	$D_7 - D_0$	D <sub>15</sub> – D <sub>0</sub>	Writes memory location $A_n$ $A_0$ .
ERAL	1	00	10XXXXXXX	10XXXXXX			Erases all memory locations. Valid only at $V_{CC}$ = 4.5V to 5.5V.
WRAL	1	00	01XXXXXXX	01XXXXXX	D <sub>7</sub> – D <sub>0</sub>	D <sub>15</sub> – D <sub>0</sub>	Writes all memory locations. Valid only at $V_{CC} = 5.0V \pm 10\%$ and Disable Register cleared.
EWDS	1	00	00XXXXXXX	00XXXXXX			Disables all programming instructions.

Notes: 1. This device is not recommended for new designs. Please refer to AT93C56A.

2. This device is not recommended for new designs. Please refer to AT93C66A.

3. The X's in the address field represent don't care values and must be clocked.





# Functional Description

The AT93C46/56/66 is accessed via a simple and versatile 3-wire serial communication interface. Device operation is controlled by seven instructions issued by the host processor. **A valid instruction starts with a rising edge of CS** and consists of a Start Bit (logic "1") followed by the appropriate Op Code and the desired memory address location.

**READ (READ):** The Read (READ) instruction contains the address code for the memory location to be read. After the instruction and address are decoded, data from the selected memory location is available at the serial output pin DO. Output data changes are synchronized with the rising edges of serial clock SK. It should be noted that a dummy bit (logic "0") precedes the 8- or 16-bit data output string.

**ERASE/WRITE (EWEN):** To assure data integrity, the part automatically goes into the Erase/Write Disable (EWDS) state when power is first applied. An Erase/Write Enable (EWEN) instruction must be executed first before any programming instructions can be carried out. Please note that once in the EWEN state, programming remains enabled until an EWDS instruction is executed or  $V_{CC}$  power is removed from the part.

**ERASE (ERASE):** The Erase (ERASE) instruction programs all bits in the specified memory location to the logical "1" state. The self-timed erase cycle starts once the ERASE instruction and address are decoded. The DO pin outputs the READY/BUSY status of the part if CS is brought high after being kept low for a minimum of 250 ns ( $t_{CS}$ ). A logic "1" at pin DO indicates that the selected memory location has been erased and the part is ready for another instruction.

**WRITE (WRITE):** The Write (WRITE) instruction contains the 8 or 16 bits of data to be written into the specified memory location. The self-timed programming cycle  $t_{WP}$  starts after the last bit of data is received at serial data input pin DI. The DO pin outputs the READY/BUSY status of the part if CS is brought high after being kept low for a minimum of 250 ns ( $t_{CS}$ ). A logic "0" at DO indicates that programming is still in progress. A logic "1" indicates that the memory location at the specified address has been written with the data pattern contained in the instruction and the part is ready for further instructions. A **READY/BUSY status cannot be obtained if the CS is brought high after the end of the self-timed programming cycle t**<sub>WP</sub>.

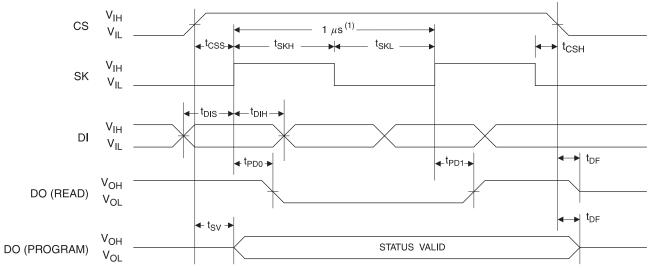
**ERASE ALL (ERAL):** The Erase All (ERAL) instruction programs every bit in the memory array to the logic "1" state and is primarily used for testing purposes. The DO pin outputs the READY/BUSY status of the part if CS is brought high after being kept low for a minimum of 250 ns ( $t_{CS}$ ). The ERAL instruction is valid only at  $V_{CC} = 5.0V \pm 10\%$ .

**WRITE ALL (WRAL)**: The Write All (WRAL) instruction programs all memory locations with the data patterns specified in the instruction. The DO pin outputs the READY/BUSY status of the part if CS is brought high after being kept low for a minimum of 250 ns ( $t_{CS}$ ). The WRAL instruction is valid only at  $V_{CC} = 5.0V \pm 10\%$ .

**ERASE/WRITE DISABLE (EWDS):** To protect against accidental data disturb, the Erase/Write Disable (EWDS) instruction disables all programming modes and should be executed after all programming operations. The operation of the READ instruction is independent of both the EWEN and EWDS instructions and can be executed at any time.

### **Timing Diagrams**

#### Synchronous Data Timing



Note: 1. This is the minimum SK period.

#### **Organization Key for Timing Diagrams**

	AT93C46 (1K)		AT93C56 (2K) <sup>(1)</sup>		AT93C66 (4K) <sup>(2)</sup>	
I/O	x 8	x 16	x 8	x 16	x 8	x 16
A <sub>N</sub>	A <sub>6</sub>	A <sub>5</sub>	A <sub>8</sub> <sup>(3)</sup>	A <sub>7</sub> <sup>(4)</sup>	A <sub>8</sub>	A <sub>7</sub>
D <sub>N</sub>	D <sub>7</sub>	D <sub>15</sub>	D <sub>7</sub>	D <sub>15</sub>	D <sub>7</sub>	D <sub>15</sub>

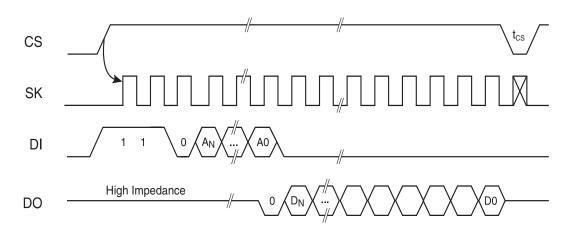
Notes: 1. This device is not recommended for new designs. Please refer to AT93C56A.

2. This device is not recommended for new designs. Please refer to AT93C66A.

3.  $A_8$  is a DON'T CARE value, but the extra clock is required.

4.  $A_7$  is a DON'T CARE value, but the extra clock is required.

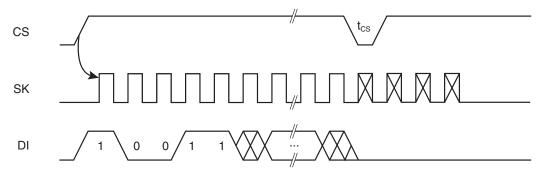
#### **READ** Timing



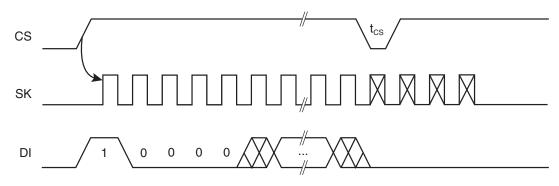




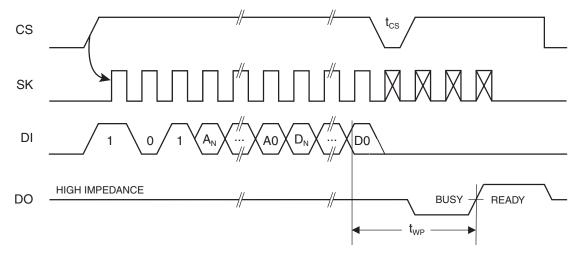
#### **EWEN** Timing



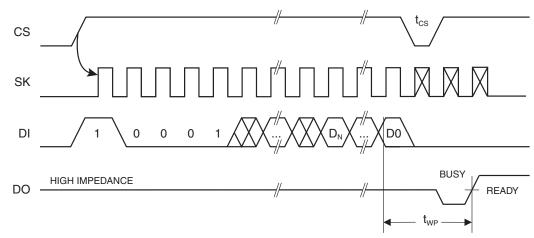
### **EWDS** Timing



### WRITE Timing

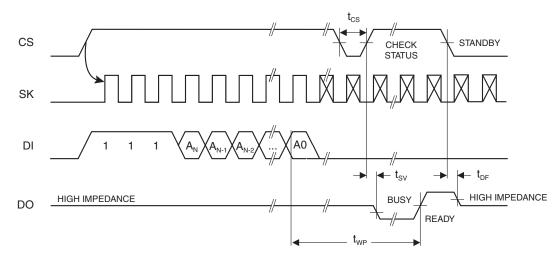


### WRAL Timing<sup>(1)</sup>



Note: 1. Valid only at  $V_{CC} = 4.5V$  to 5.5V.

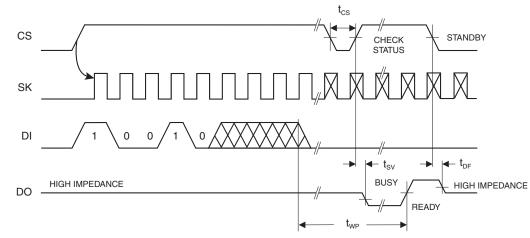
#### **ERASE** Timing







### ERAL Timing<sup>(1)</sup>



Note: 1. Valid only at  $V_{CC}$  = 4.5V to 5.5V.

### AT93C46 Ordering Information

Ordering Code	Package	Operation Range	
AT93C46-10PI-2.7	8P3		
AT93C46-10SI-2.7	8S1		
AT93C46R-10SI-2.7	8S1	la du atria l	
AT93C46W-10SI-2.7	8S2		
AT93C46-10TI-2.7	8A2	(–40°C to 85°C)	
AT93C46U3-10UI-2.7	8U3-1		
AT93C46Y1-10YI-2.7	8Y1		
AT93C46-10PI-1.8	8P3		
AT93C46-10SI-1.8	8S1		
AT93C46R-10SI-1.8	8S1	la du atria l	
AT93C46W-10SI-1.8	8S2		
AT93C46-10TI-1.8	8A2	(–40°C to 85°C)	
AT93C46U3-10UI-1.8	8U3-1		
AT93C46Y1-10YI-1.8	8Y1		
AT93C46-10SU-2.7	8S1	Lead-Free/Halogen-Free/	
AT93C46-10SU-1.8	8S1		
AT93C46-10TU-2.7	8A2	Industrial Temperature	
AT93C46-10TU-1.8	8A2	(–40°C to 85°C)	
AT93C46-10SE-2.7	8S1	High Grade/Extended Temperature (-40°C to 125°C)	

Note: For 2.7V devices used in the 4.5V to 5.5V range, please refer to performance values in the AC and DC characteristics table.

Package Type			
8P3	8-lead, 0.300" Wide, Plastic Dual Inline Package (PDIP)		
8S1	8-lead, 0.150" Wide, Plastic Gull Wing Small Outline (JEDEC SOIC)		
8S2	8-lead, 0.200" Wide, Plastic Gull Wing Small Outline (EIAJ SOIC)		
8A2	8-lead, 0.170" Wide, Thin Shrink Small Outline Package (TSSOP)		
8U3-1	8-ball, die Ball Grid Array Package (dBGA2)		
8Y1	8-lead, 4.90 mm x 3.00 mm Body, Dual Footprint, Non-leaded, Miniature Array Package (MAP)		
	Options		
-2.7	Low-voltage (2.7V to 5.5V)		
-1.8	Low-voltage (1.8V to 5.5V)		
R	Rotated Pinout		





# AT93C56<sup>(1)</sup> Ordering Information

Ordering Code <sup>(2)</sup>	Package	Operation Range	
AT93C56-10PI-2.7	8P3		
AT93C56-10SI-2.7	8S1	Industrial	
AT93C56W-10SI-2.7	8S2		
AT93C56-10TI-2.7	8A2	(−40°C to 85°C)	
AT93C56Y1-10YI-2.7	8Y1		
AT93C56-10PI-1.8	8P3		
AT93C56-10SI-1.8	8S1	Industrial	
AT93C56W-10SI-1.8	8S2		
AT93C56-10TI-1.8	8A2	(–40°C to 85°C)	
AT93C56Y1-10YI-1.8	8Y1		

Note: 1. This device is not recommended for new designs. Please refer to AT93C56A.

2. For 2.7V devices used in the 4.5V to 5.5V range, please refer to performance values in the AC and DC characteristics table.

Package Type		
8P3	8-lead, 0.300" Wide, Plastic Dual Inline Package (PDIP)	
8S1	8-lead, 0.150" Wide, Plastic Gull Wing Small Outline (JEDEC SOIC)	
8S2	8-lead, 0.200" Wide, Plastic Gull Wing Small Outline (EIAJ SOIC)	
8A2	8-lead, 0.170" Wide, Thin Shrink Small Outline Package (TSSOP)	
8Y1	8-lead, 4.90 mm x 3.00 mm Body, Dual Footprint, Non-leaded, Miniature Array Package (MAP)	
Options		
-2.7	Low-voltage (2.7V to 5.5V)	
1.8	Low-voltage (1.8V to 5.5V)	

# AT93C66<sup>(1)</sup> Ordering Information

Ordering Code <sup>(2)</sup>	Package	Operation Range	
AT93C66-10PI-2.7	8P3		
AT93C66-10SI-2.7	8S1	Industrial	
AT93C66W-10SI-2.7	8S2	Industrial	
AT93C66-10TI-2.7	8A2	(–40°C to 85°C)	
AT93C66Y1-10YI-2.7	8Y1		
AT93C66-10PI-1.8	8P3		
AT93C66-10SI-1.8	8S1	Inductrial	
AT93C66W-10SI-1.8	8S2	Industrial (–40°C to 85°C)	
AT93C66-10TI-1.8	8A2		
AT93C66Y1-10YI-1.8	8Y1		

Notes: 1. This device is not recommended for new designs. Please refer to AT93C66A.

2. For 2.7V devices used in the 4.5V to 5.5V range, please refer to performance values in the AC and DC characteristics table.

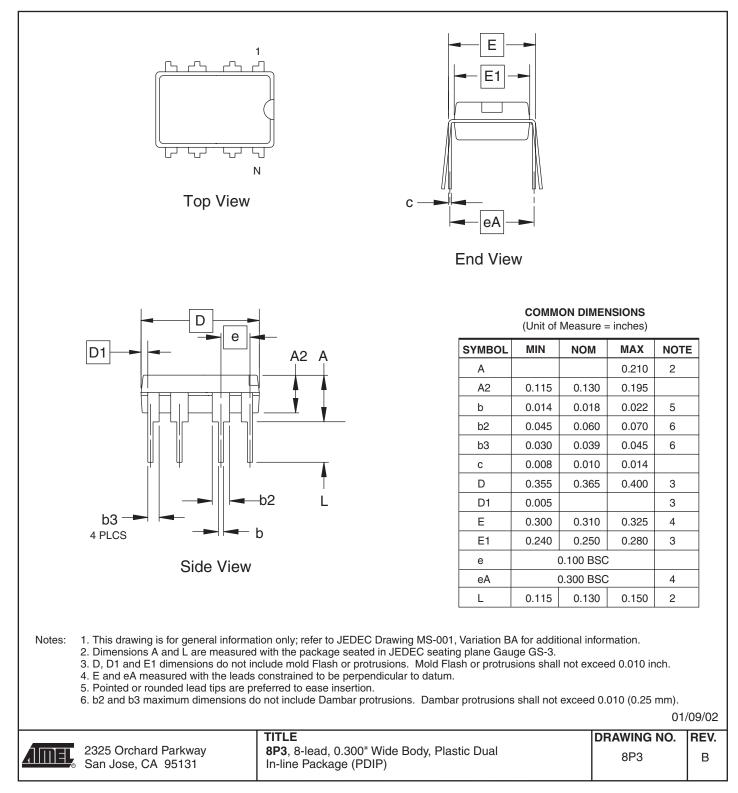
Package Type		
8P3	8-lead, 0.300" Wide, Plastic Dual Inline Package (PDIP)	
8S1	8-lead, 0.150" Wide, Plastic Gull Wing Small Outline (JEDEC SOIC)	
8S2	8-lead, 0.200" Wide, Plastic Gull Wing Small Outline (EIAJ SOIC)	
8A2	8-lead, 0.170" Wide, Thin Shrink Small Outline Package (TSSOP)	
8Y1	8-lead, 4.90 mm x 3.00 mm Body, Dual Footprint, Non-leaded, Miniature Array Package (MAP)	
Options		
-2.7	Low-voltage (2.7V to 5.5V)	
-1.8	Low-voltage (1.8V to 5.5V)	

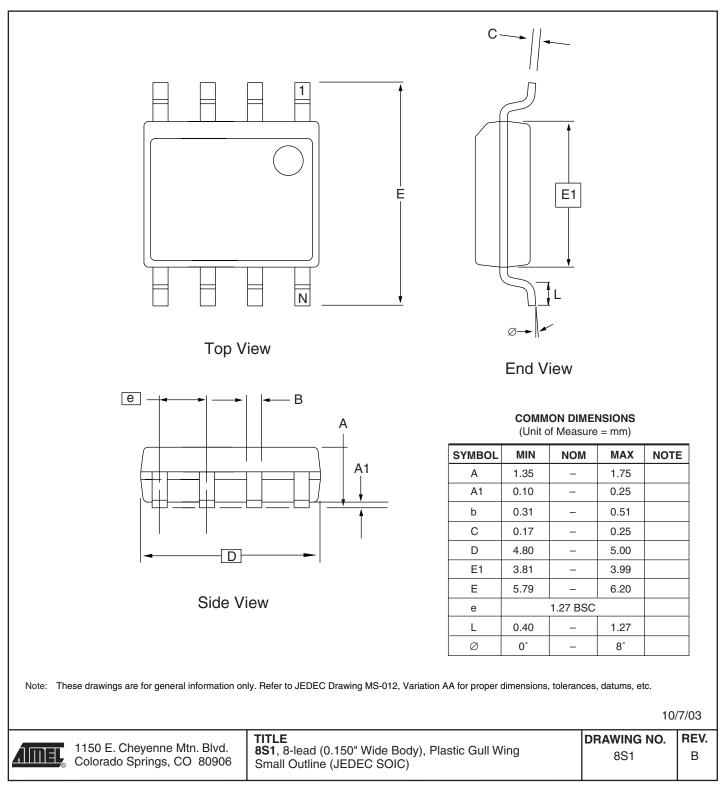




#### **Packaging Information**

#### 8P3 – PDIP

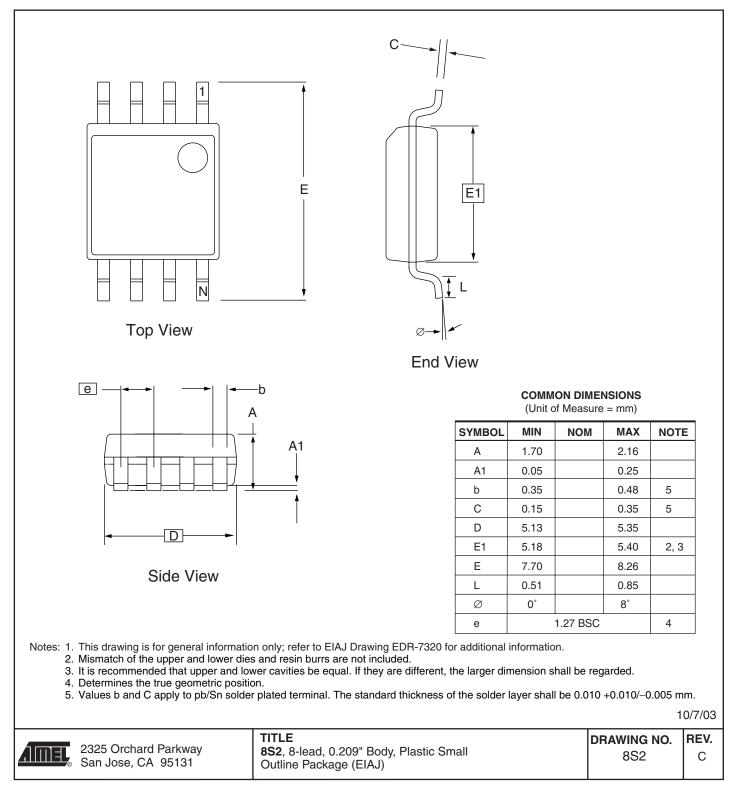


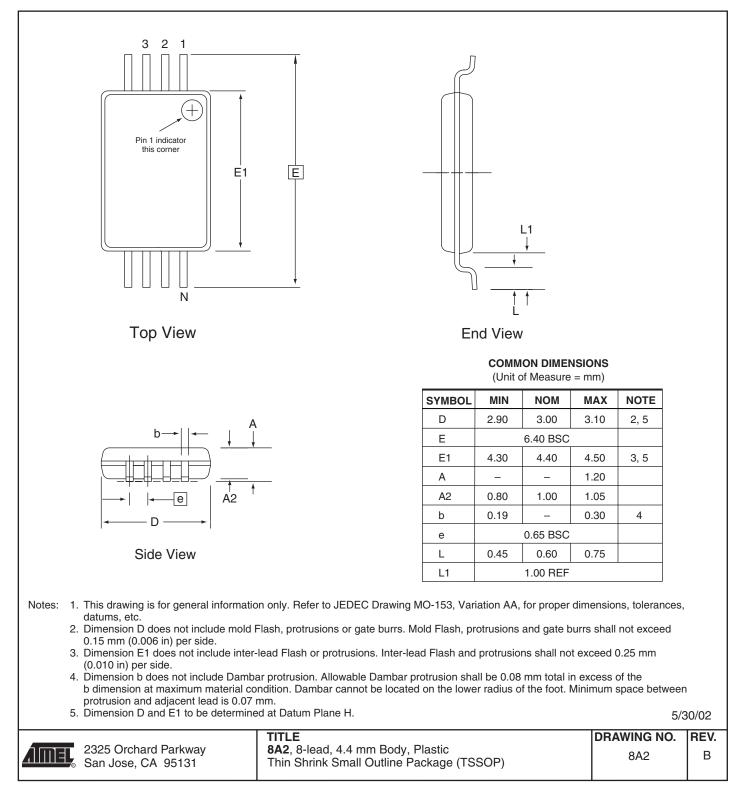






#### 8S2 – EIAJ SOIC

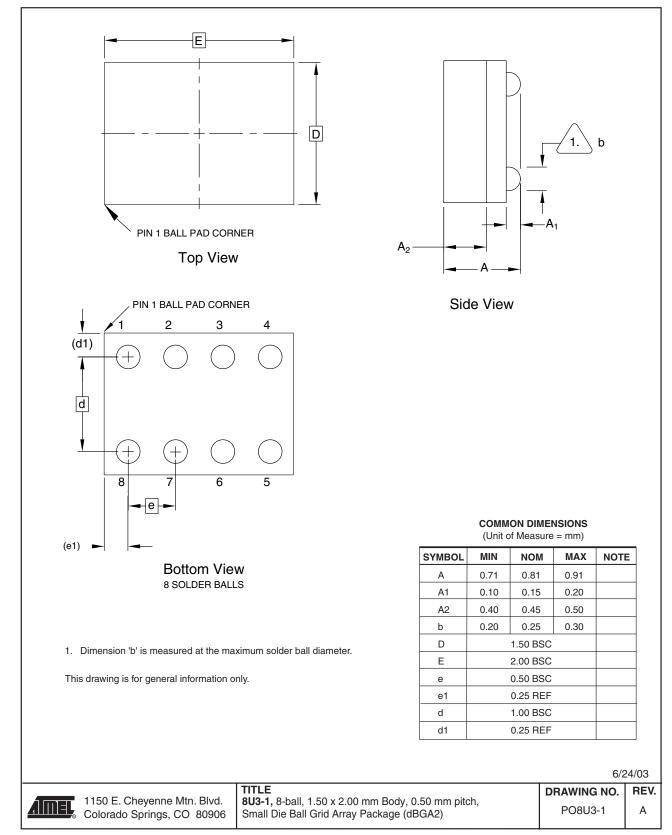


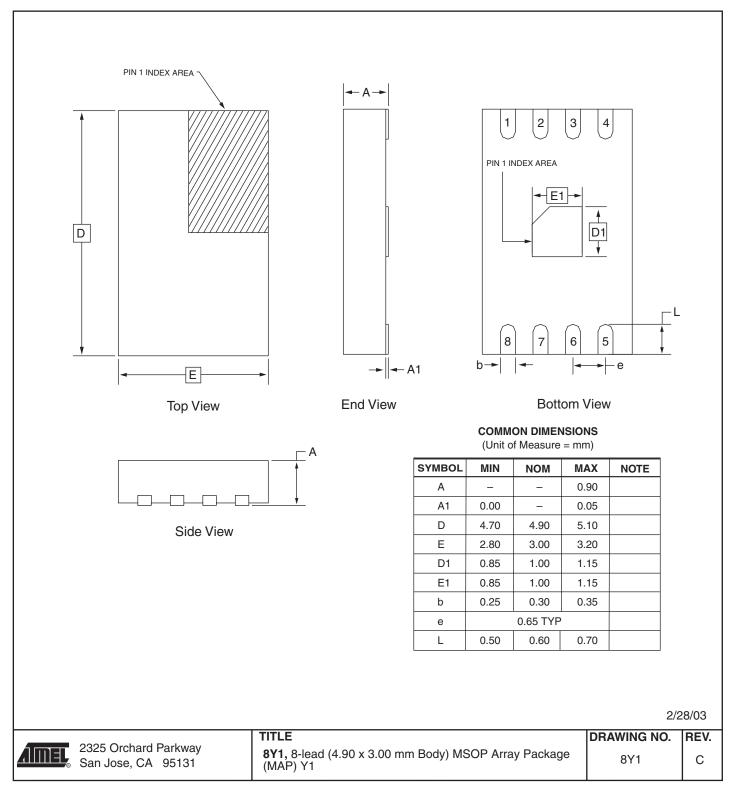






#### 8U3-1 - dBGA2









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